Correlations between Immobilizing Ions and Suppressing Hysteresis in Perovskite Solar Cells

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ABSTRACT: Ion migration has been regarded as the major cause of photocurrent hysteresis. Here we use photoluminescence (PL) and optical images, combined with Galvanostatic measurement, to detect the ionic motion. We observe an irreversible PL and optical transmittance change after electric poling. By comparing a neat perovskite film with the sample coated by poly(methyl methacrylate) (PMMA), polyethylene glycol (PEG), and [6,6]-phenyl-C61-butryic acid methyl ester (PCBM), we found that PCBM effectively inhibits ionic motion near the surface of the perovskite. We further evidenced the donor−acceptor complex formed between PCBM and perovskite, implying the mechanism of inhibited ion migration by PCBM. We close by demonstrating that PCBM can also be introduced on the top of perovskite film in an n−i−p TiO2 planar structure, to achieve an average 14% steady-state output over $2.3 \times 10^5$ s (∼64 h). This work highlights the importance of inhibiting ionic motion in perovskite solar cells.

Organometal trihalide perovskites, typically CH$_3$NH$_3$PbI$_3$ (MAPbI$_3$), are attractive light-absorber materials in the photovoltaic field, owing to efficient ambipolar transport behavior and large optical absorption. Although solution-processed perovskite solar cells (PSCs) have great advantages of low cost and convenient manufacture, there are two obstacles that remain for commercial application, photocurrent hysteresis and performance stability. The hysteresis makes it confusing and difficult to evaluate the actual power conversion efficiency (PCE) of PSCs. So far, it is still very challenging to achieve hysteresis-free devices in and n−i−p structure, and the longest holding time at the maximum power point (MPP) was usually reported within a few hundred seconds in the architecture containing TiO$_2$. Ion migration has been confirmed in the organometal halide perovskite film and has been considered as a major cause for the observed hysteresis. Considering the fact that ionic mobility is very small with a long relaxation time, it can be related to the current hysteresis and other slow processes observed in PSCs.

In this work, we developed an integrated method, Galvanostatic measurement, in situ photoluminescence measurement before and after electric poling, and real time recording of optical microscopic images to characterize ion migration in perovskite films. Moreover, by comparing the perovskite film with many coating layers ([6,6]-phenyl-C61 butyric acid methyl ester (PCBM), poly(methyl methacrylate) (PMMA), and polyethylene glycol (PEG)), we found that PCBM has a special effect on inhibiting ionic motion, and we attributed the hysteresis-free behavior in inverted PSCs to the inhibited ionic motion by PCBM, in addition to the previously mentioned mechanisms. Further characterizations revealed that PCBM can form a strong bond with undercoordinated atoms at the exposed surface of a perovskite film. After that, we further found that devices with TiO$_2$ n−i−p structure also present significantly suppressed hysteresis and improved stability (around 64 h stability in MPP tracking) if PCBM chemically absorbed on the exposed surface of perovskite film.

To characterize ion migration in a perovskite film under an applied electric field, a setup is established to realize in situ photoluminescence (PL) characterization with standard Galvanostatic measurement, as is illustrated in Figure 1a. In this setup, the lateral structure (Au/perovskite/Au) was specifically fabricated to realize this in situ characterization,
and the dynamic process is recorded using both PL spectra and applied voltage. Unless otherwise stated, the measurements are conducted in ambient air. For Galvanostatic measurement, a standard method to characterize ion migration in the ionic conductor is used; upon switching the current from 0 nA to a preset value of 10 nA, the voltage instantaneously reaches $\sim 1\text{V}$ and then gradually increases to a larger value of $\sim 18\text{V}$ (Figure 1b). During this slow process, both the electron and ion contribute to the conductivity, $j = (\sigma_{\text{ion}} + \sigma_{\text{electron}})E$. As ions gradually accumulate at the two sides, a compositional gradient to block the current gradually forms. This blocking effect demands a larger voltage to retain the constant current (10 nA). At last, the voltage increases to the saturation value where only electronic conductivity exists (Figure 1b). This slow process strongly suggests that ionic transport exists in the film with an extremely small diffusion coefficient of $\sim 10^{-18}\text{cm}^2\text{s}^{-1}$ compared to that of electronic transport, $10^{-4}\text{cm}^2\text{s}^{-1}$.

Considering the fact that ion migration will induce excess defects (VI, MA) in the film, especially at the two sides of a sample, in situ PL characterization is used here to further confirm this process. PL intensity decreases after the voltage switches on at both the anode and cathode by approximately 1 order of magnitude in 6 s (Figure 1c,d), indicating that defect states increase in the perovskite film with time after applying an electric field across the film. In addition, the peak position after electric poling has no visible shift near the cathode pole (Figure 1c), while a large blue shift from 767 to 757 nm is observed near the anode (Figure 1d), which may originate from the strong band-filling effect induced by $V_i$ with n-doping. Moreover, an irreversible process for the PL spectra after switching off the current is observed (Figure S1, Supporting Information), as is consistent with the decay process in Figure 1b. This irreversible process implies that a change of PL intensity will be maintained after electric poling, which is consistent with results by Xiao et al. With that in mind, we further move on to use PL mapping in a fixed region of about $30 \times 50 \mu m^2$ on a perovskite film before and after 10 s of electric poling ($\sim 0.35\text{V/\mu m}$) along the $x$ direction (Figure 2a,b). The PL intensity in the entire region has a similar value before electric poling (Figure 2a), but it evolves into a quasi-Gaussian distribution after poling (Figure 2b). The PL intensity decreases most significantly at the electrode sides, almost 1/6 of that in the middle position. This distribution resembles an ionic distribution as predicted in macroscopic theory of mixed conduction. As is expected below, the largest variation of stoichiometric excess or vacancy of mobile ions is located at the two electrodes, $N = N_0 + A(x/L - 0.5)$, where $N_0$ is the initial concentration, $L$ is the length of the sample ($50\mu m$), and $A$ is a constant depending on the ionic conductivity of the material. The significantly quenched PL can...
be reasonably attributed to the excess defect states induced by ionic motion, where the two sides of the film have the largest amount of defect states (Figure 2b). More than that, PL mapping on the peak position also presents an obvious difference before and after electric poling (Figure S2, Supporting Information), consistent with the results in Figure 1d.

Accelerated ionic motion under a high field of 1 V/μm can cause image contrast change under optical microscopic observation (Figure 2c,d), as schematically shown in the measurement setup in Figure 1a. The contrast change from panel c to d in Figure 2 is possibly due to the composition or morphology change during electric poling of a lateral structure device. The snapshots of this dynamic process (Figure 2d) demonstrate the drift of ions in the film, with more black dots appearing at the anode. These black dots may come from the loss of iodine in the area close to the anode if the I⁻ ion is the main migration species, although the MA⁺ ion was also reported. The finding of ion drift in optical imaging is generally in agreement with previous study by Xiao et al.21

The above observations suggest that ion drift under an electric field introduces defect states in the perovskite film. To further support our scenario on the density of defect states induced by ion migration, we use density function theory (DFT) calculation to reveal how these stable defect states are formed when ion migration occurs. Details of DFT calculation are shown in the Supporting Information. The underlying physical picture and simulation results are demonstrated in Figure 3. Iodine-rich and iodine-poor conditions will be realized in different areas of the perovskite film after electric poling, as is shown in Figure 3a,c. Differing from previous calculations in the bulk of the film, in our slab model, deep-level defects will form near the film surface due to I trimers and Pb dimers in Figure 3a−c (∼0.3 eV below the conduction band minimum (CBM)), serving as nonrecombination centers (Figure 3d−f).30 This result offers powerful evidence of our explanation of the PL quenching behavior observed in Figure 2b.

By using these characterization methods, we further move on to detect the influence of different coating layers on ionic motion in the perovskite. Here, PMMA, PEG, and PCBM are selected to spin-coat on the perovskite film, and lateral devices are fabricated. We observe that optical images and PL spectra show little change during 1 min of poling (1 V/μm) after the three material coatings (Figure S3), compared with the drastic change in the control sample. We also conduct experiments in vacuum and find that optical images present indiscernible change if we put the sample in vacuum system (1 μTorr) under the same poling condition (Figure S3, Supporting Information). These results are consistent with those of T. Leijten et al.23 that moisture can enhance the ionic motion in perovskites and that any coating layers on the perovskite or in vacuum conditions can relieve the detrimental effect induced by ambient moisture. This irreversible interaction with water under bias is vividly demonstrated, implying the importance to conduct stability tests with strict encapsulation. More than that, for the conductance and Galvanostatic measurements in the

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Figure 2. PL mapping tests on a 30 × 50 μm² region of perovskite film before (a) and after (b) the aforementioned Galvanostatic measurement with ~0.35 V/μm. Optical microscopic image of the perovskite film before (c) and after (d) accelerated electric poling at 1 V/μm for 20 s.

Figure 3. Iodine-rich and iodine-poor conditions will be realized in different areas of the perovskite film after electric poling, as is shown in Figure 3a,c. Differing from previous calculations in the bulk of the film, in our slab model, deep-level defects will form near the film surface due to I trimers and Pb dimers in Figure 3a−c (∼0.3 eV below the conduction band minimum (CBM)), serving as nonrecombination centers (Figure 3d−f).30 This result offers powerful evidence of our explanation of the PL quenching behavior observed in Figure 2b.
lateral device, these samples with a PMMA/PEG coating and in vacuum still present hysteresis and slow process (Figure S4). However, after PCBM treatment, the hysteresis has been significantly suppressed compared to the control sample (Figure 4a). Furthermore, only the PCBM coating sample shows a much faster response time (0.06 and 0.2 s) compared to the very slow voltage response time constant of around 2.5 and 8.5 s in the control sample (Figure 4b). The above results strongly suggest a stronger inhibiting effect of ion migration by PCBM. PCBM is not just a moisture-resistant layer but may have other effects to inhibit ionic motion. This result, in turn, suggests that the Galvanostatic characterization has higher sensitivity to evidence the inhibited ionic motion.

As we know, PCBM is normally used to suppress hysteresis in inverted structures due to defect passivation and electron extraction. Although Sargent et al. proposed that PCBM may also inhibit ion migration to suppress hysteresis, it still lacks evidence. With that in mind, compared with other coating layers, we speculate that PCBM can also strongly bond with perovskites, leading to inhibited ionic motion. We further use liquid-state ¹H NMR measurements to prove whether strong interaction exists between fullerenes and ions on the exposed surface of perovskites. The proton NMR spectra of four samples were compared (Figure 4c): deuterated DMSO solution with PCBM (sample 1), with MAI (sample 2), with PCBM + MAI (sample 3), and PCBM + PbI₂ (sample 4). In the signals of sample 1, the methylene group close to the ester bond in PCBM is characterized by the peak at δ = 1.533, and a visible chemical shift Δδ = 0.083 of this peak in samples 3 and 4 with PbI₂ and MAI, indicating interaction between iodine and PCBM. However, the proton resonance signal of −NH₃⁺ in MAI presents a small shift from 7.522 to 7.531 ppm, indicating a very weak dipole interaction of MA⁺ with the fullerene. For the interaction between the halogen and fullerene, the donor–acceptor nature due to charge transfer had previously been proven by Raman spectra, electron paramagnetic spectra (EPR), and absorption spectroscopy. To directly confirm this strong interaction, here we devise a dissolution experiment for 3 mg mL⁻¹ C₆₀ with three solvents: methylbenzene (C₇H₈), iodobenzene (C₆H₅I), and chlorobenzene (C₆H₅Cl). When hydrogen in benzene is substituted for halogen (I/Cl), the C₆₀ solubility correspondingly increases, which can be evidenced by a weakened Tyndall effect when a red laser beam passes through the solution, as shown in Figure 4d. This increased solubility should be independent of the polarity of the solvent due to the nonpolarity of C₆₀. To summarize, PCBM can interact with I⁻ in the perovskite film due to charge transfer to a buckyball and the van der Waals force with butyric acid methyl ester.

We close by demonstrating a new method of introducing PCBM into the perovskite film in n-i-p structure devices by immersing the as-prepared perovskite film in PCBM chloroform solution. Figure 3. (a–c) Atomic structure of two-dimensional perovskite (CH₃NH₃)₃Pb₂I₇ viewed along the direction perpendicular to the z-axis. Color scheme: Pb: gold; I: purple; C: dark gray; N: blue; H: white. After adding an electric field, the I trimer can be induced in the I-poor region (a) and the Pb dimer can be induced in the I-rich region (c), compared to the initial crystal structure (b). Red circles in (a) and (c) represent the I trimer and Pb dimer, respectively. (d–f) Calculated band structure plot for intact (e), V1⁻ (d), and IMA⁺ (f) along G(0,0,0) to F(0,1/2,0) to Q(0,1/2,1/2) to Z(0,0,1/2) to G(0,0,0). For defect V1⁻, there is an occupied defect state that lies below the perovskite CBM by 0.24 eV, which is shown by the red line. For IMA⁺, formation of an I trimer introduces an empty defect state close to (~0.35 eV) the bulk CBM, shown by the red line.
obenzene solution (Figure 5a). Immersion time optimization is shown in Figure S5a. We perform the time-resolved photo-luminescence (TRPL) test for three batches of samples: the control sample, the perovskite film after PCBM immersion, and the perovskite film after PCBM spin-coating. As presented in Figure 5b, PL spectra show a striking difference between spin-coated and immersed samples. The PCBM spin-coated sample shows corresponding lifetimes of 2.5 and 18.3 ns by using biexponential fitting, indicating a strong quenching effect. Very different from the spin-coated case, the PCBM-immersion sample shows a much longer minority carrier lifetime close to 101.5 ns by using single-exponential fitting, similar to the control sample. This result proves that PCBM will not cause the electron reflux here, and the improved hysteresis does not originate from an effective quenching effect by PCBM. Mass spectrometry (SIMS) measurements (Figure S6) reveal the PCBM distribution by this method, that PCBM penetrates into the film through grain boundaries and chemically absorb on the surface of the perovskite.

SEM characterization shows little difference in surface morphology after PCBM immersion (Figure S6). Current hysteresis is significantly decreased for the corresponding devices (Figure 5c). As a result, the PCBM-immersed sample demonstrates a higher steady-state efficiency of 15.6% than that (8%) of the control sample (Figure 5d). More importantly, the PSCs after PCBM immersion show a much better long-term stability in steady-state measurement mode, maintaining an approximately average 14% PCE for as long as ~2.3 × 10^5 s (64 h) of continuous output at MPP, compared to the quickly degraded PCE in control devices (Figure 5d).

Furthermore, after PCBM immersion, the perovskite film has a much faster response than that of the control sample in Galvanostatic measurements with ion blocking electrodes (Figure S7). On the basis of the above results plus the impedance spectra analysis (Figure S5), we speculate that the improved stability and suppressed hysteresis by PCBM immersion may originate from the inhibited ionic motion by PCBM. The influence of chlorobenzene is excluded because devices with 16 h immersion in the solvent without PCBM present no improvement in efficiency and hysteresis.

In summary, by introducing the integrated method to detect ion migration, a close relation has also been built up between ion migration and hysteresis in PSCs. We offer evidence on the posit that PCBM can inhibit ionic motion to suppress current hysteresis in PSCs by moisture resistance and donor–acceptor bonding. We close by demonstrating that hysteresis and stability can also be improved in the TiO2 n–i–p structure if the PCBM molecule is chemically absorbed on the exposed surface and grain boundaries of the perovskite film. Enlightened by these results above, we speculate that hysteresis can be eliminated if ion migration is minimized in PSCs.
Figure 5. (a) Illustration diagram for the device preparation and PCBM immersion method. (b) TRPL characteristics for three batches of samples: control, with PCBM immersion treatment, and with PCBM spin-coating and annealing treatment. (c) Current–voltage (I–V) characteristics for devices with and without PCBM immersion treatment. (d) Steady-state efficiency at MPP as a function of time for devices with and without PCBM immersion treatment. Continuously working at a 0.7 V bias, the efficiency was recorded every 1 s. Devices went through 16 h of continuous work at MPP under AM1.5 illumination without any optical filter in the glovebox (humidity < 0.1 ppm) followed by 8 h of being stored in the dark for every 24 h.

ASSOCIATED CONTENT

Supporting Information
The Supporting Information is available free of charge on the ACS Publications website at DOI: 10.1021/acsenergylett.6b00060.

 Experimental methods and DFT calculation methods; PL spectra change at positive and negative poling after the current switches off; PL mapping of the peak position of the perovskite film before and after electric poling; optical image of the PMMA-coated sample in air and the control sample in vacuum; conductance and Galvanostatic measurements for the PMMA-coated perovskite film in air and the control sample in vacuum; PCBM immersion time optimization process; impedance spectra analysis; SEM characterization and SIMS measurements of the perovskite film before and after PCBM immersion; Galvanostatic measurements of PCBM-immersed and control samples (PDF)

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Notes
The authors declare no competing financial interest.

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